

## P-Channel 40-V (D-S) MOSFET

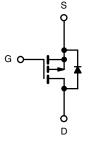
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	r <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
- 40	0.0041 at V <sub>GS</sub> = - 10 V	- 110	185 nC		

#### **FEATURES**

• TrenchFET<sup>®</sup> Power MOSFET







P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 40	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	
	T <sub>C</sub> = 25 °C		- 110 <sup>a</sup>	
Continuous Droin Current (T 175 °C)	T <sub>C</sub> = 70 °C		- 110 <sup>a</sup>	
Continuous Drain Current ( $T_J = 175 \ ^{\circ}C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	39 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		33 <sup>b, c</sup>	A
Pulsed Drain Current		I <sub>DM</sub>	240	A
Continuous Courses Ducia Diada Current	T <sub>C</sub> = 25 °C	1	110	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	10 <sup>b, c</sup>	
Avalanche Current		I <sub>AS</sub>	75	
Single-Pulse Avalanche Energy	valanche Energy L = 0.1 mH		281	mJ
	T <sub>C</sub> = 25 °C		375	
Maximum Davier Disaination	T <sub>C</sub> = 70 °C	Б	262	14/
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	15 <sup>b, c</sup>	W
	T <sub>A</sub> = 70 °C		10.5 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C
Soldering Recommendations (Peak Temperature		260		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	8	10	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	0.33	0.4	°C/W	

Notes:

a. Package limited. b. Surface Mounted on 1" x 1" FR4 board. c. t = 10 s. d. Maximum under Steady State conditions is 40 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static		· · · · · · · · · · · · · · · · · · ·				
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 40			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 40		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 5.5		mv/ C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 2	- 3	- 4	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zara Cata Valtaga Drain Current	I <sub>DSS</sub>	$V_{DS} = -40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-1			
Zero Gate Voltage Drain Current		$V_{DS}$ = - 40 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 120			А
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 20 A		0.0041		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 20 A		75		S
Dynamic <sup>b</sup>		· · · · · · · · · · · · · · · · · · ·			l.	
Input Capacitance	C <sub>iss</sub>			11300		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		1510		
Reverse Transfer Capacitance	C <sub>rss</sub>			1000		
Total Gate Charge	Qg			185	280	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -20 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -110 \text{ A}$		48		
Gate-Drain Charge	Q <sub>gd</sub>			42		
Gate Resistance	Rg	f = 1 MHz		4.0		Ω
Turn-On Delay Time	t <sub>d(on)</sub>			25	40	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 0.18 $\Omega$		290	440	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 110 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		110	165	- ns
Fall Time	t <sub>f</sub>			35	55	
Drain-Source Body Diode Characteristic	s	·		•		•
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			- 110	А
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	I <sub>SM</sub>			- 240	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 20 A		- 0.8	- 1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			70	105	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 20 A, di/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		130	200	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$F_{\rm F} = -20$ A, $u/ul = 100$ A/µs, $T_{\rm J} = 25$ °C		37		ns
Reverse Recovery Rise Time	t <sub>b</sub>	1		33		

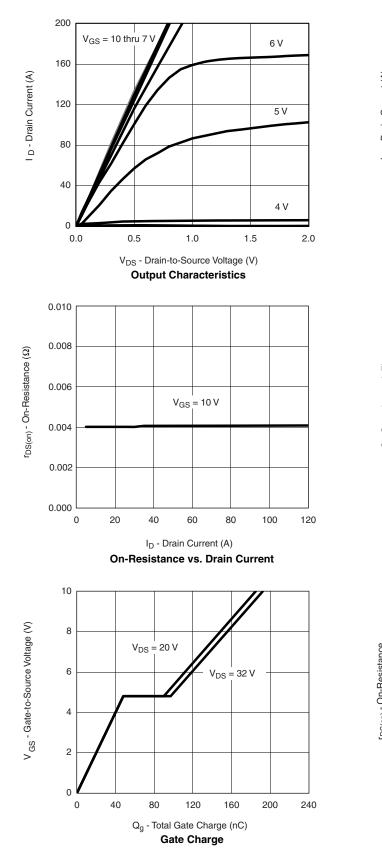
Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

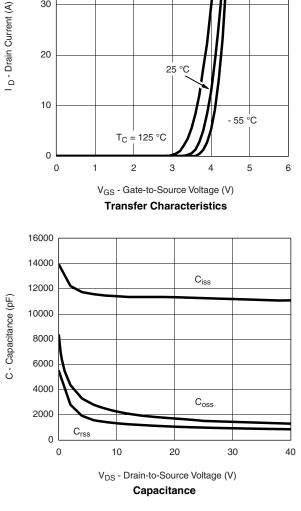
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



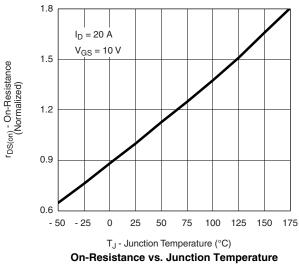


### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

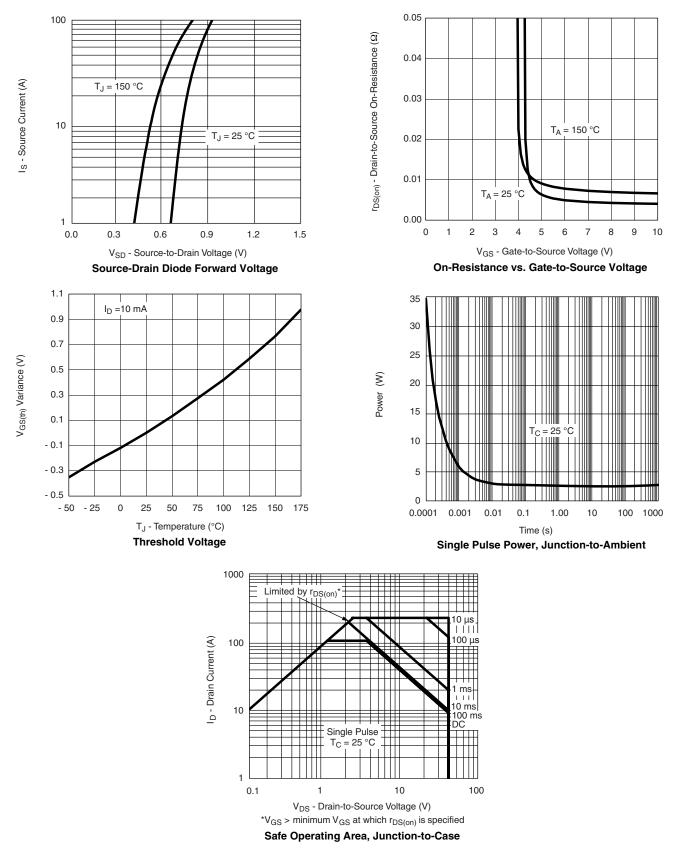


40

30

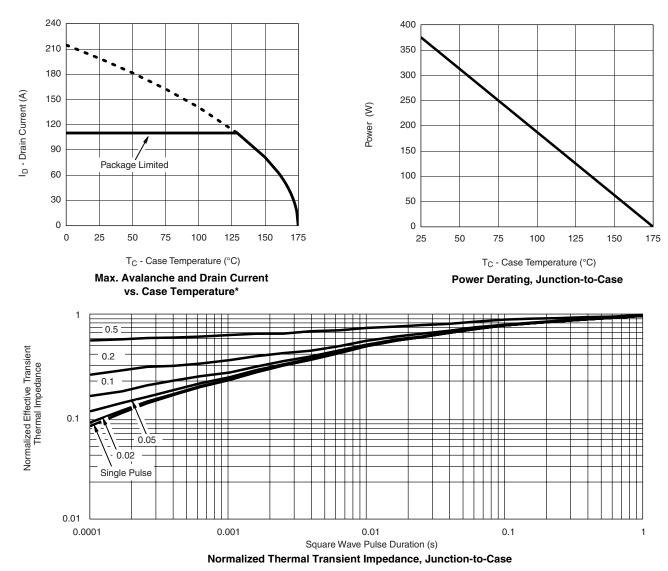






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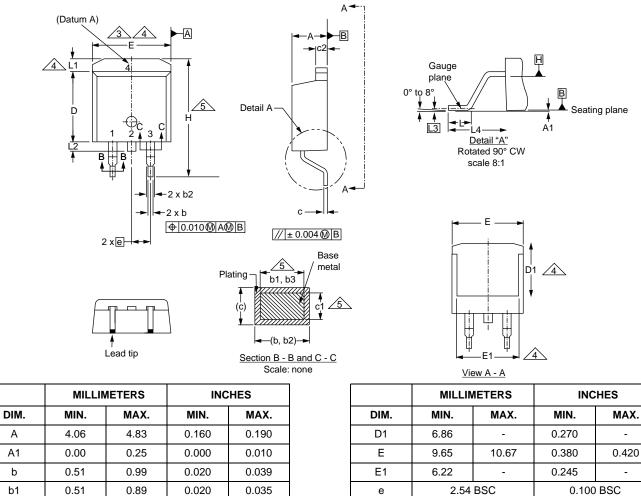


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



### **TO-263AB**



С	0.38	0.74	0.015	0.029		
c1	0.38	0.58	0.015	0.023		
c2	1.14	1.65	0.045	0.065		
D	8.38	9.65	0.330	0.380		
ECN: S-82110-Rev. A, 15-Sep-08 DWG: 5970						

1.78

1.73

0.045

0.045

0.070

0.068

#### Notes

b

b2

b3

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

1.14

1.14

3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.

Н

L

L1

L2

L3

L4

14.61

1.78

-

-

4.78

0.25 BSC

15.88

2.79

1.65

1.78

5.28

0.575

0.070

-

-

0.188

0.625

0.110

0.066

0.070

0.208

0.010 BSC

4. Thermal PAD contour optional within dimension E, L1, D1 and E1.

5. Dimension b1 and c1 apply to base metal only.

6. Datum A and B to be determined at datum plane H.

7. Outline conforms to JEDEC outline to TO-263AB.



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